

**9**

component, said substrate has Euler angles of approximately (0°, 125°–147°, 0°±5°), and said normalized film thickness H/λ is within the range of approximately 0.003 to 0.05.

**9.** A surface acoustic wave device according to claim 1, wherein said interdigital transducer includes Zn as a major component, said substrate has Euler angles of approximately (0°, 125°–138°, 0°±5°), and said normalized film thickness H/λ is within the range of approximately 0.003 to 0.05.

**10.** A surface acoustic wave device according to claim 1, wherein said interdigital transducer includes W as a major component, said substrate has Euler angles of approximately (0°, 125°–138°, 0°±5°), and said normalized film thickness H/λ is within the range of approximately 0.002 to 0.05.

**11.** A communication device including the surface acoustic wave device according to claim 1.

**12.** A communication device including the surface acoustic wave device according to claim 2.

**10**

**13.** A communication device including the surface acoustic wave device according to claim 3.

**14.** A communication device including the surface acoustic wave device according to claim 4.

**15.** A communication device including the surface acoustic wave device according to claim 5.

**16.** A communication device including the surface acoustic wave device according to claim 6.

**17.** A communication device including the surface acoustic wave device according to claim 7.

**18.** A communication device including the surface acoustic wave device according to claim 8.

**19.** A communication device including the surface acoustic wave device according to claim 9.

**20.** A communication device including the surface acoustic wave device according to claim 10.

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